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	IFOF	A TION	DIC	CL OCUDE	Application Number	09/876,915	
				CLOSURE	Filing Date	June 8, 2001	
STATEMENT BY APPLICANT					First Named Inventor	Wilhelm	
					Art Unit	2624	
	(Use as many she	ets as	necessary)	Examiner Name	Desire, G.	
Sh	neet	1	of	1	Attorney Docket Number	46872-254525	

NON PATENT LITERATURE DOCUMENTS							
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T 2				
/GD/	1	EDGEWORTH, R. et al., "Adaptive sampling for coordinate metrology," Precision Engineering, Vol. 23, pp. 144- 154, 1999.					
/GD/	2	EDGEWORTH, R. et al., "Measurement uncertainty due to work-piece error interaction with sampling period," Center of Precision Metrology, Department of Mechanical Engineering and Engineering Science, The University North Carolina at Charlotte, 1999.					
/GD/	3	ELKOTT, D. et al., "Isoparametric line sampling for the inspection planning of sculptured surfaces," Computer- Aided Design, Vol. 37, pp. 189-200, 2005.					
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/GD/	5	ELKOTT, D. et al., "Automatic sampling for CMM inspection planning of free-form surfaces," International Journal of Production Research, Vol. 40, No. 11, pp. 2653-2676, 2002.					
/GD/	6	HUANG, J., 'An efficient approach for solving the straightness and the flatness problems at large number of data points,' Computer-Aided Design, Vol. 35, pp. 15-25, 2003.					
/GD/	7	PEDONE, P. et al., "Kriging-based sequential inspection plans for coordinate measuring machines," Applied Stochastic Models in Business and Industry, Vol. 25, pp. 133-149, 2009.					
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/GD/	10	WILHELM, R. et al., "Task specific uncertainty in coordinate measurement," Center for Precision Metrology, Department of Mechanical Engineering and Engineering Science, University of North Carolina at Charlotte, USA. (2001).					
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